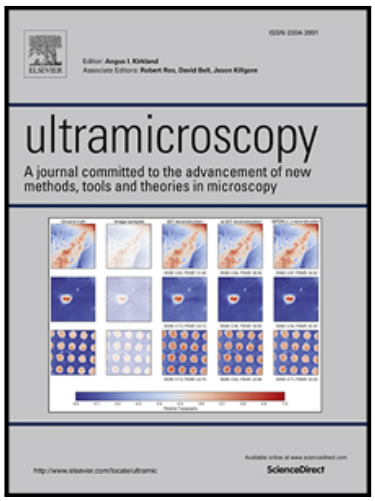

A new method for mapping the three-dimensional atomic distribution within nanoparticles by atom probe tomography (APT)

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Highlight

- Pd and Pt/C nanoparticles were embedded in Ni films by means of electrophoresis and electrodeposition.
- Atom Probe Tomography (APT) specimens were fabricated from the embedded nanoparticles using focused ion beam milling.
- While Pt/C specimens showed uneven field evaporation and reconstruction artifacts, mass spectra and APT reconstructions of high data integrity could be obtained for the Pd nanoparticle specimens.